

A scalable model based RTL framework zamiaCAD for static analysis

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Applications of the open source HW design framework zamiaCAD

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Assessment of diagnostic test for automated bug localization

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Automated design error localization in RTL designs

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Identification and rejuvenation of NBTI-critical logic paths in nanoscale circuits

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Rejuvenation of NBTI-impacted processors using evolutionary generation of assembler programs

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VHDL design debug framework based on zamiaCAD

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